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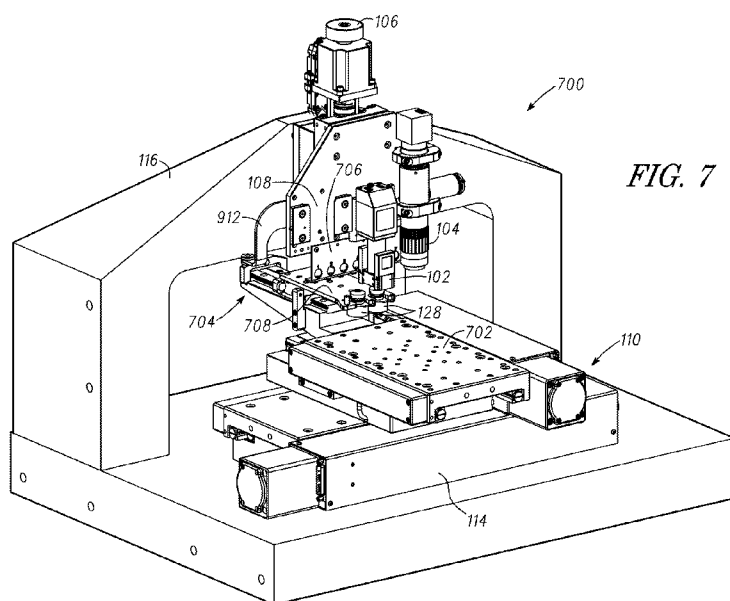
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- (54) **Title:** INSTRUMENT CHANGING ASSEMBLY AND METHODS FOR THE SAME

**FIG. 7**

(57) **Abstract:** A first instrument changing assembly includes a magazine having one or more probe assembly stations. The assembly further includes at least one probe change tool including a receptacle socket. One or more probe assemblies are retained within the one or more probe assembly stations. The one or more probe assemblies each include a probe receptacle including a probe retention recess and a common socket fitting configured for complementary fitting with a common receptacle socket. The probe change tool is configured to install or extract the respective probes from a mechanical testing instrument according to the complementary fit between the common socket fitting and the common receptacle socket of the probe assemblies. A second instrument changing assembly includes an instrument array housing including a plurality of instruments. Each of the one or more instruments (probe and transducer combination) are deployed relative to the instrument array housing with an instrument deployment actuator.